

Search Notes

Application/Control No.

10/082,176

Examiner

Tse Chen

Applicant(s)/Patent under
Reexamination

HASEGAWA, TOSHITAKA

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text search only - see search rpt prtout	10/12 - 10/20/05	TSE